

Search Notes



Application/Control No.

10/670,154

Examiner

Mark K. Han

Applicant(s)/Patent under Reexamination

TROCKI ET AL.

Art Unit

3767

SEARCHED

Class	Subclass	Date	Examiner
604	93.01 118	10/1/2006	mbh.
	121		
	131		
	151		
	152		
	154		
	181		
	187		
	500		
	507		
	508		
	533		
	534		
	535		
600	431		
	432		
128	898		
	dig. 1		
	dig. 12		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST text search	10/1/2006	mbh.